

Notice of References Cited	Application/Control No. 10/784,763		Applicant(s)/Patent Under Reexamination JASAPARA ET AL.	
	Examiner Denise B. Anderson		Art Unit 2877	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,633,712	05-1997	Venkatesh et al.	356/503
*	B	US-5,731,876	03-1998	Venkatesh et al.	356/503
*	C	US-6,661,502	12-2003	Jakobsen et al.	356/73.1
*	D	US-6,961,123	11-2005	Wang et al.	356/364
*	E	US-5,565,986	10-1996	Knuttel, Alexander	356/456
*	F	US-2005/0190371	09-2005	Knuttel, Alexander	356/479
*	G	US-2005/0140981	06-2005	Waeilti, Rudolf	356/479
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	DE10207186	02-2002	DE	Knuttel, Alexander	G01B,Go1N
	O	PCT/CH05302	04-2002	CH	Waeilt, Rudolf	
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Massig et al. Fringe-pattern analysis with high accuracy by use of the Fourier-transform method: theory and experimental tests; Applied Optics; 1 May 2001; Vol 40, No. 13; pp 2081-2088
	V	Froggat et al. All-fiber wavemeter and Fourier-transfoorm spectrometer; Optics Letters; 15 July 1999; Vol. 24; No. 14;pp. 942-944
	W	Nishimura et al. Mode-field expansion and reduction in dispersive fibers by local heat treatments. IEEE Journal of Selected Topics in Quantum Electronics, Vol. 5, No. 5, September/October 1999, pages 1260-1265.
	X	Jauncey et al. Narrow-linewidth fiber laser operating aty 1.55 microns. Optics Letters; Vol. 12; No. 3; March 1987; p. 164-165.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.